

BACK-END

MOS-FET

IGBT

DIODE

SEMICONDUCTOR TEST SYSTEM 半導体テストシステム

CHT1050Z

1000V
500A

NEW

- CHT1050Z is DC measurement tester with a built-in multi-pin scanner to measure multi-element module. Measurement is carried out with an application by setting device to jig unit (left part in the picture). The information and measurement result of the device are displayed with the application.
- CHT1050Zは多素子モジュール測定に対応した多ピンスキャナ内蔵のDCテスターです。製品写真左側の治具ユニットにデバイスをセットし測定を行い、専用のアプリケーションソフトで通信を行い、製品の情報や測定結果を表示します。

MODEL		CHT1050Z
SOFTWARE		
TEST PLAN/SORT PLAN		1000/1000
BIN OUT		24
DC UNIT		
MEASURABLE DEVICES		MOS-FET, IGBT, DIODE
VOLTAGE/CURRENT		1000V/500A
TEST ITEMS		
MOS-FET	IDS, IGS, ISG, BVDS, VP, VTH, VTHsub, VTH2, VTH2sub, VDSOn, RdsOn, LVdsOn, LRdsOn, VfsDs, IdOn, DHIDSS, GMP	
IGBT	ICE, IGE, IEG, BVCE, VP, VTH, VTHsub, VTH2, VTH2sub, VCEOn, LVCEOn, VFECs, ICoN, GMP	
DIODE	IR, VR, VF	
DIMENSIONS & WEIGHT		
TEST UNIT		550(W)×880(D)×1700(H)…210kg
JIG UNIT		900(W)×650(D)×1700(H)…150kg



Scanner Setting Display

